

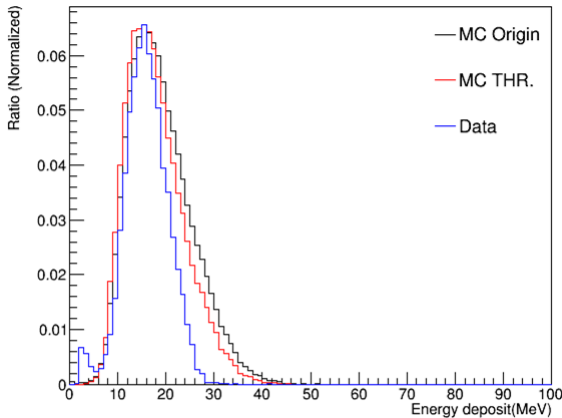


Analysis Status of ZDC ECal

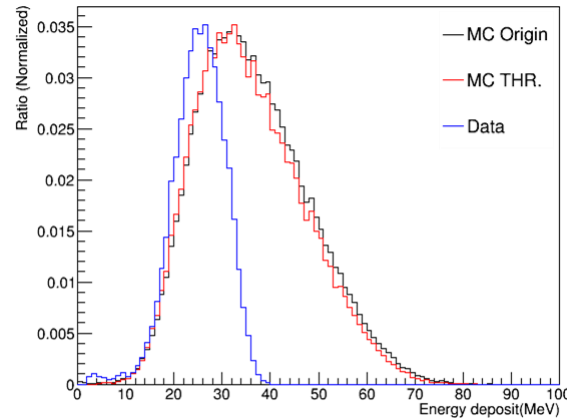
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Inconsistency between Data and MC

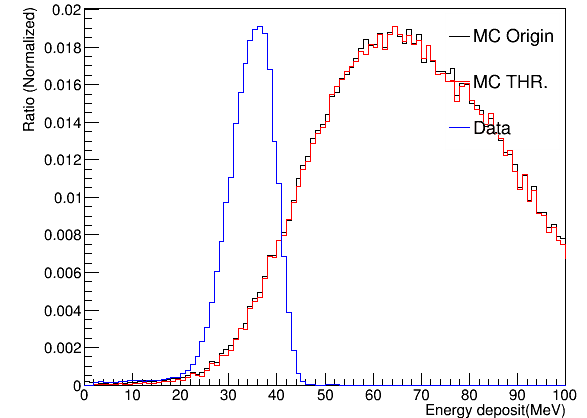
47MeV



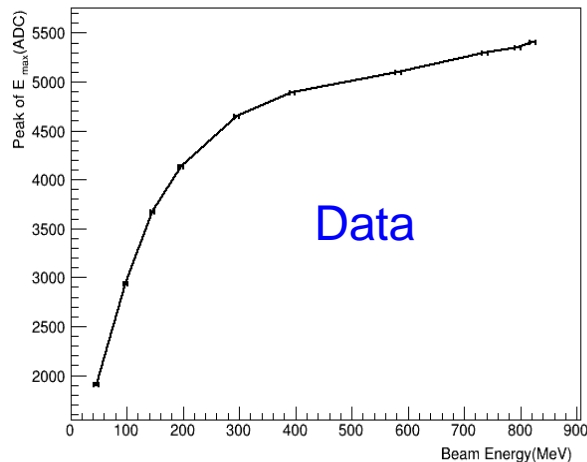
98MeV



198MeV

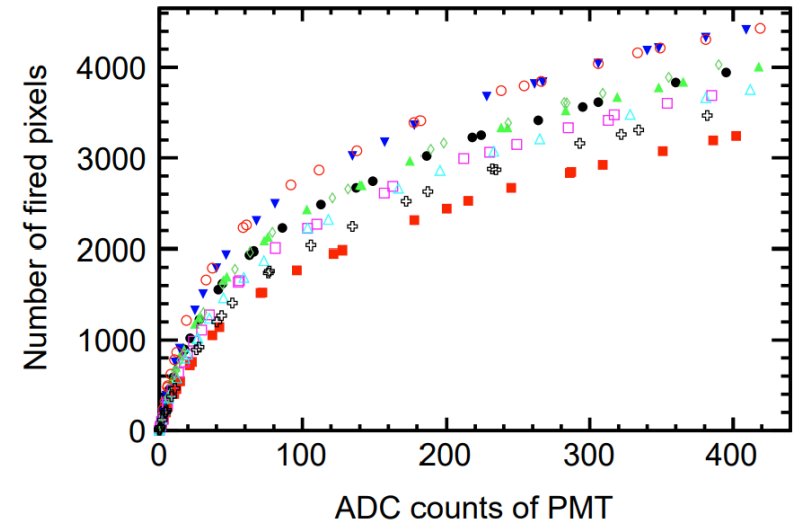
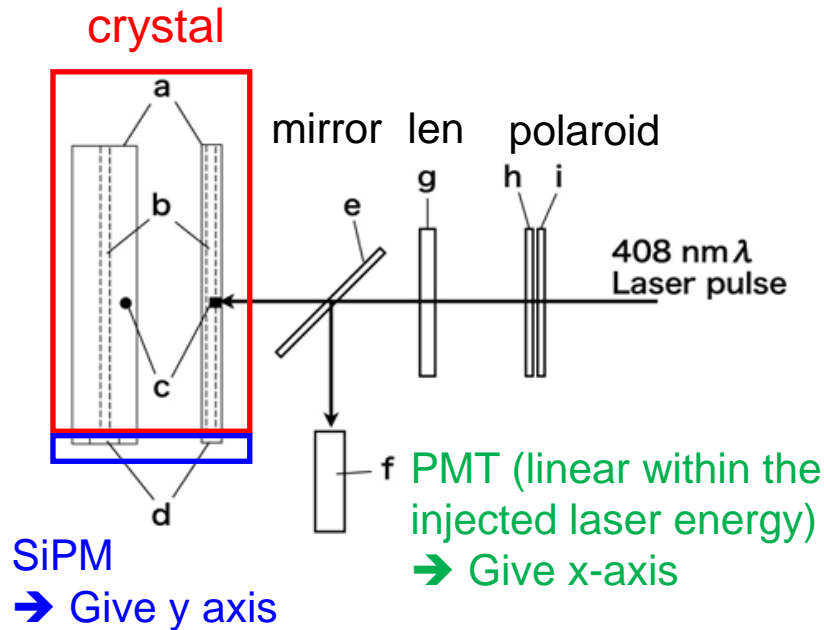


Beam Energy VS peak of E_{max}



- Threshold has implemented in MC, but still can't find the consistency between data and MC. Only features of LYSO crystal are implemented in MC but not.
- How to describe SiPM behavior and input into MC?

Description of SiPM Behavior



<https://arxiv.org/abs/1510.01102>

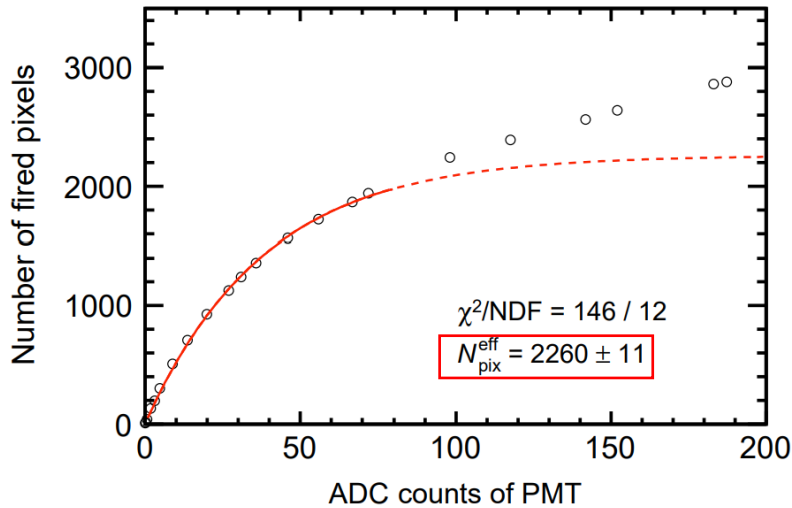
Correlation between laser intensity and number of fired pixel of SiPM

X : ADC count of PMT \rightarrow intensity of incident laser

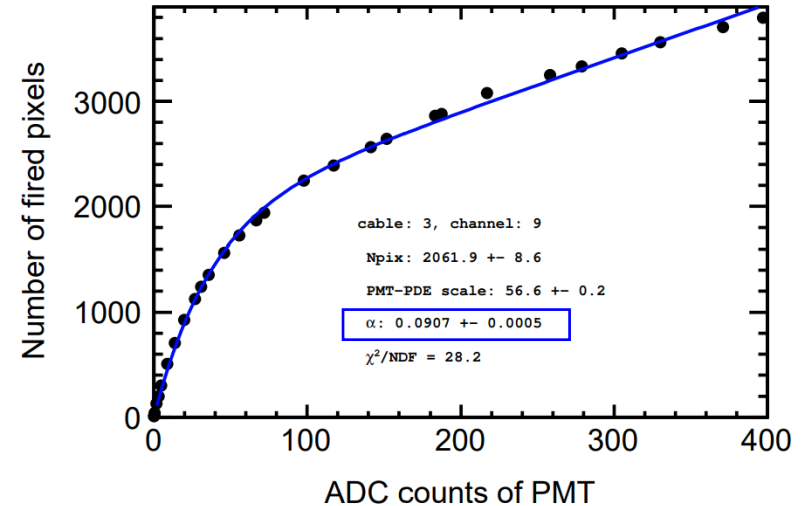
Y : Number of fired pixel \rightarrow ADC of SiPM output divided by ADC of single pixel SiPM output

Description of SiPM Behavior

LO $\rightarrow \epsilon, N_{pix}$



NLO $\rightarrow \alpha$



$$N_{fire}^{LO} = N_{pix} \left[1 - \exp\left(-\frac{\epsilon N_{in}}{N_{pix}}\right) \right]$$

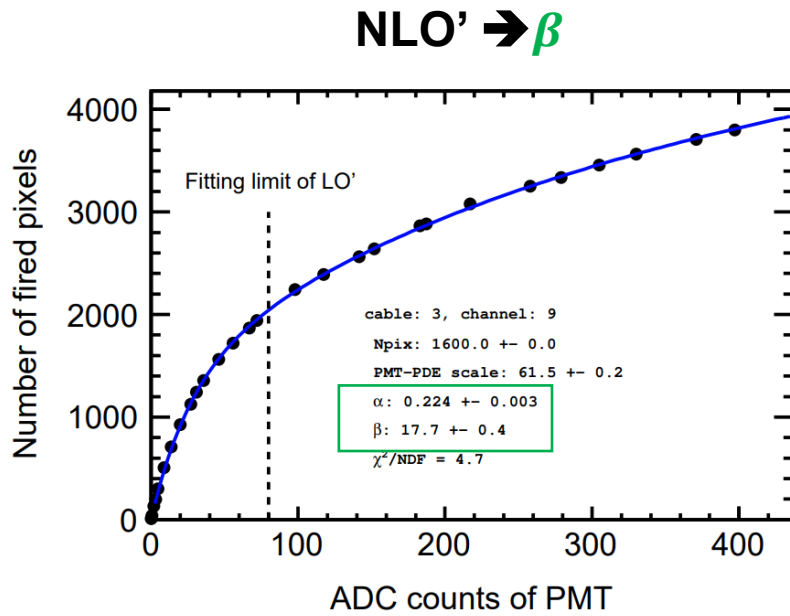
$$N_R = \epsilon N_{in} - N_{fire}^{LO}$$

$$N_{fire}^{NLO} = N_{fire}^{LO} + \alpha N_R$$

- N_{fire}^{LO} = Num. of fired pixel of SiPM
- N_{pix} = Num of pixel of SiPM
- ϵ = photon detection efficiency of SiPM

- N_R = rest of photons do not detected by SiPM at the first time.
- α = average contribution of remaining photons.

Description of SiPM Behavior



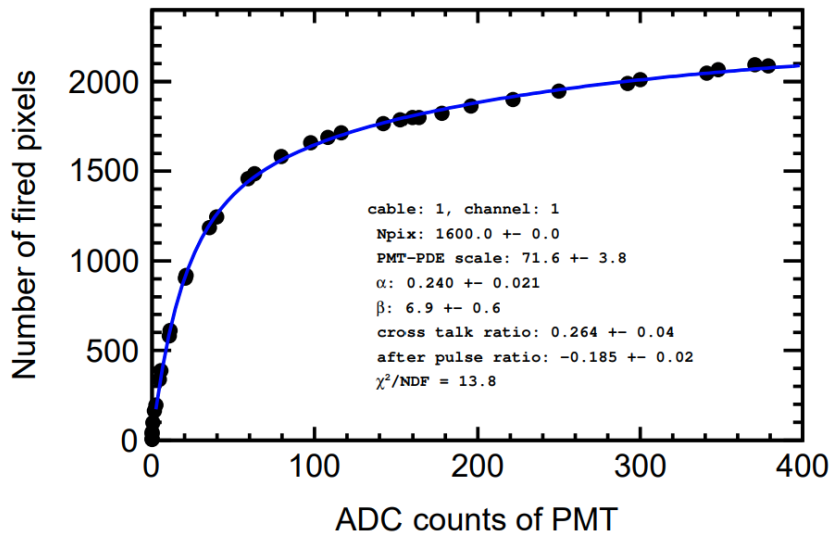
NLO : α gives the average charge contribution of remaining photon.

NLO' : β gives the charge contribution of remaining photon and it decreases as the number of photons on a pixel increases.

$$N_{\text{fire}}^{\text{NLO}'} = N_{\text{fire}}^{\text{NLO}} \frac{\beta + 1}{\beta + \epsilon N_{\text{in}}/\text{LO}}$$

Description of SiPM Behavior

NLO' + Cross talk and after pulse



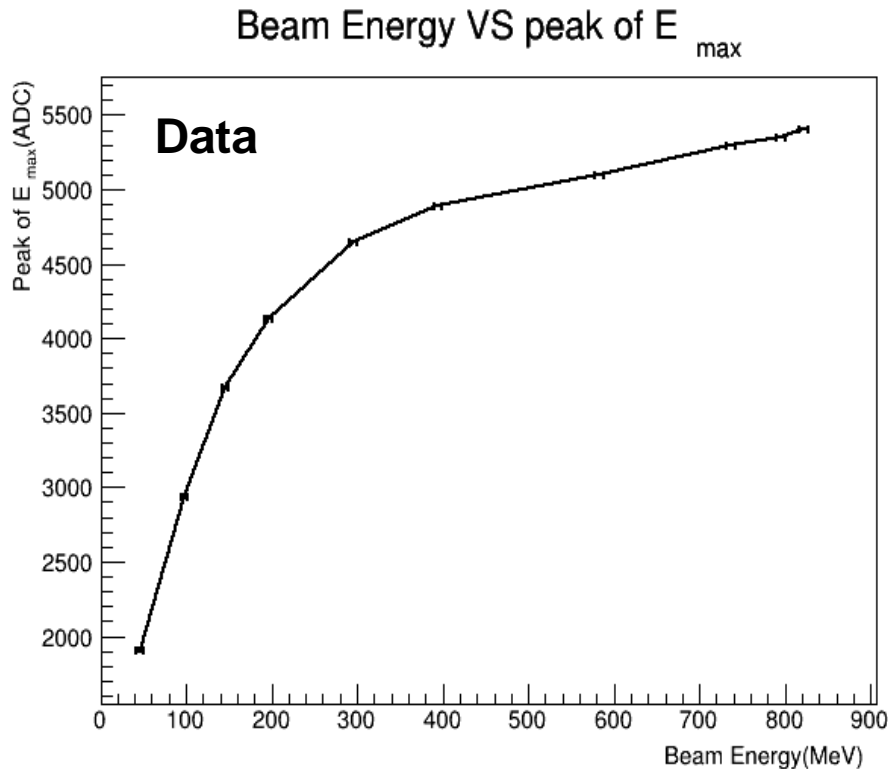
$$N_{\text{fire}}^{\text{NLO}'_{\text{C.A}}} = N_{\text{fire}}^{\text{NLO}'} \left(1 + P_{\text{cross}} \cdot e^{-\epsilon N_{\text{in}}/N_{\text{pix}}} \right) \cdot (1 + P_{\text{after}})$$

Crosstalk occurs when a photon, created by the primary avalanche, subsequently induces a second avalanche in a neighboring pixel.

An after pulse occurs when a second avalanche is seeded by the release of an electron trapped in a lattice defect of the depletion zone, or a hole diffuses toward the depleted layer and, consequently, induces a second avalanche. The hole is created by a photon in the same mechanism as the crosstalk, and this diffusion delays the after pulses because the electric field of the bulk is weak.

Both results the increase in the average number of fired pixels.

Access the Behavior of SiPM from Data (1)



LO \rightarrow
 ϵ, N_{pix}

$$N_{fire}^{LO} = N_{pix} \left[1 - \exp\left(-\frac{\epsilon N_{in}}{N_{pix}}\right) \right]$$

NLO $\rightarrow \alpha$

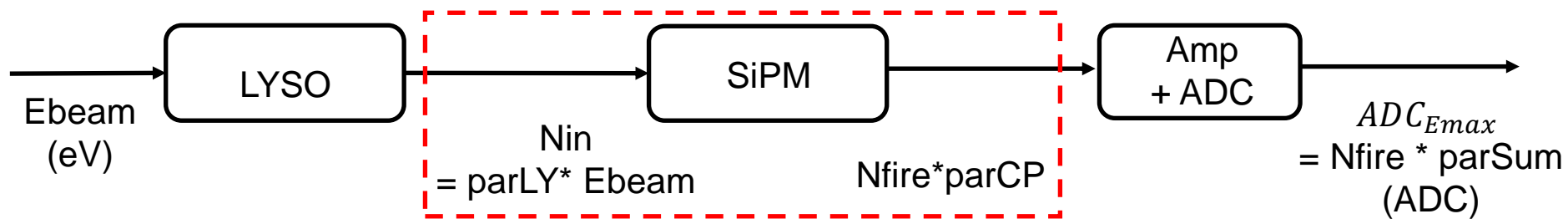
$$N_R = \epsilon N_{in} - N_{fire}^{LO}$$
$$N_{fire}^{NLO} = N_{fire}^{LO} + \alpha N_R$$

NLO' $\rightarrow \beta$

$$N_{fire}^{NLO'} = N_{fire}^{NLO} \frac{\beta + 1}{\beta + \epsilon N_{in}/LO}$$

Can our data adopt to the fit?

Access the Behavior of SiPM from Data (2)



Paper describes the relation between N_{in} and N_{fire}

In LYSO :

- ① $E_{beam} \rightarrow N_{\text{photon/eV}}$ (Photon Detection Efficiency) \rightarrow Birk's law (light yield saturation effect)
- ② $N_{in} = [(N_{\text{photon/eV}}) * \text{Birk}] * E_{beam} = \text{parLY} * E_{beam}$
- ③ **parLY includes the effect of PDE and Birk's law**

In SiPM :

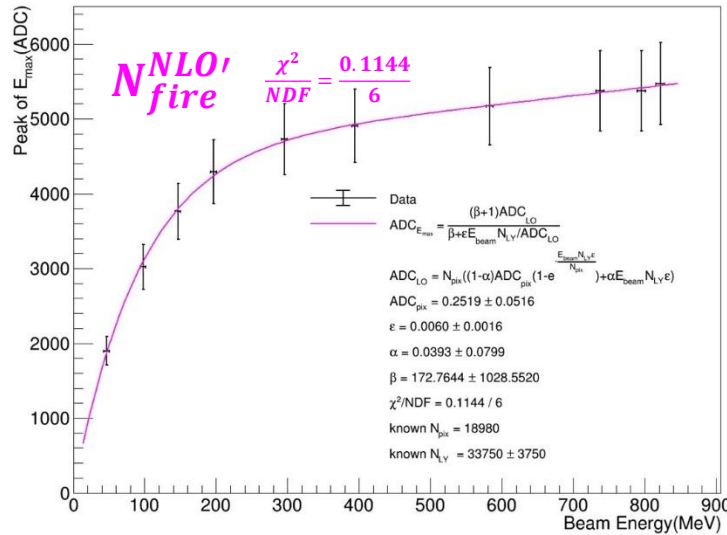
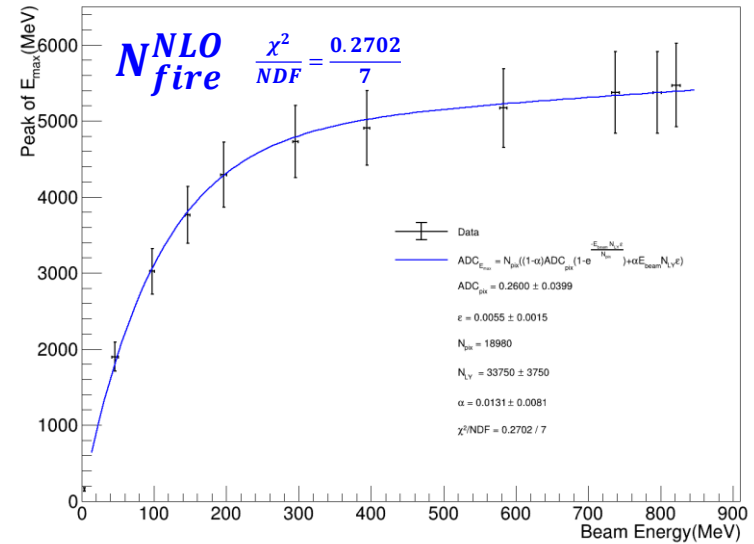
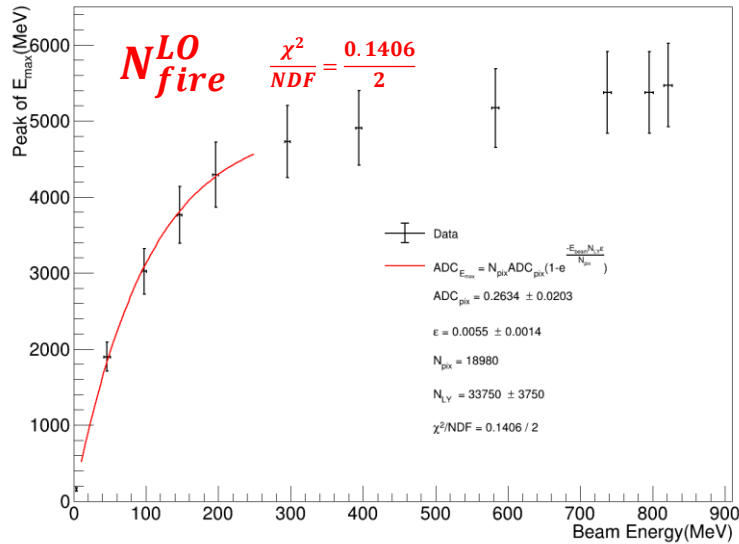
- ① Effect : **photon detection eff, correction of charge for "rest photon", cross talk, after pulse**
- ② Relation between N_{fire} and N_{in} : $N_{fire}^{LO}, N_{fire}^{NLO}, N_{fire}^{NLO'}, N_{fire}^{NLO'(CA)}$
- ③ Convert N_{fire} to charge, **$N_{fire} * \text{parCP}$**

In Amp + ADC :

- ① Amplification : parAmp
- ② Voltage to digit : parADC
- ③ Final output from electronic = $N_{fire} * \text{parCP} * \text{parAmp} * \text{parADC} = \text{Nfire} * \text{parSum} = ADC_{Emax}$
- ④ Where N_{fire} , one can describe by the formula explained earlier

$$\text{Use LO as example : } ADC_{Emax} = N_{fire} * \text{parSum} = N_{pix} \left[1 - \exp \left(- \frac{(\epsilon * \text{parLY}) * E_{beam}}{N_{pix}} \right) \right] * \text{parSum}$$

Access the Behavior of SiPM from Data (3)



- 10% uncertainty added to data points after considering the energy convergent factor and fitting quality of peak energy.
- Fitting quality looks nice. Better chi2/ndf after considering higher order.
- All the parameters looks reasonable, except for β .

Access the Behavior of SiPM from Data (4)

	Parameters			Note.
N_{fire}^{LO}	$\epsilon * N_{LY}$	Light yield of SiPM	$(0.0055 \pm 0.0014) * (33750 \pm 3750)$	Fit
	N_{pix}	Num. of pixel of SiPM	18980	Fixed, from manual
N_{fire}^{NLO}	α	average charge contribution of one rest photon	0.00393 ± 0.0799	Fit
	N_{pix}	Num. of pixel of SiPM		Fixed, from manual
	$\epsilon * N_{LY}$	Light yield of SiPM		Fixed, from LO fit
$N_{fire}^{NLO'}$	β	charge contribution of one photon decreases as the number of photons on a pixel increases	172.7644 ± 1028.5520	Fit Why large uncertainty?
	$\epsilon * N_{LY}$	Light yield of SiPM	$(0.0060 \pm 0.0016) * (33750 \pm 3750)$	Fit
	N_{pix}	Num. of pixel of SiPM		Fixed, from manual
	α	average charge contribution of one rest photon		Fixed, from NLO fit

- We will investigate fitting of $N_{fire}^{NLO'}$.
- We could already implement SiPM behavior in MC with N_{fire}^{NLO} fitting results.

Summary

- We try to implement SiPM behavior into MC to have better agreement. The first step, obtain the parameters of SiPM description, is done. We will see the outcome of MC with it in the near future.